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# AOD414, AOD414L( Green Product ) N-Channel Enhancement Mode Field Effect Transistor

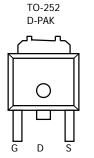
## **General Description**

The AOD414 uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , shoot-through immunity and body diode characteristics. This device is ideally suited for use as a low side switch in CPU core power conversion. AOD414L ( Green Product ) is offered in a lead-free package.

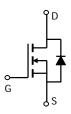
#### **Features**

 $V_{DS}(V) = 30V$  $I_{D} = 85A$ 

 $R_{DS(ON)} < 5.2 m\Omega \text{ (V}_{GS} = 10 \text{V)}$  $R_{DS(ON)} < 7.0 m\Omega \text{ (V}_{GS} = 4.5 \text{V)}$ 



Top View Drain Connected to Tab



Absolute Maximum Ratings T <sub>A</sub> =25°C unless otherwise noted								
Parameter		Symbol	Maximum	Units				
Drain-Source Voltage		$V_{DS}$	30	V				
Gate-Source Voltage		$V_{GS}$	±20	V				
Continuous Drain	T <sub>C</sub> =25°C <sup>G</sup> 85		85					
Current B,G	T <sub>C</sub> =100°C <sup>B</sup>	$I_D$	73	Α				
Pulsed Drain Current		I <sub>DM</sub>	200	7				
Avalanche Current <sup>C</sup>		I <sub>AR</sub>	30	А				
Repetitive avalanche energy L=0.1mH <sup>C</sup>		E <sub>AR</sub>	140	mJ				
	T <sub>C</sub> =25°C	D	100	W				
Power Dissipation B	T <sub>C</sub> =100°C	-P <sub>D</sub>	50	VV				
	T <sub>A</sub> =25°C	D	2.5	\\\				
Power Dissipation A	T <sub>A</sub> =70°C	P <sub>DSM</sub>	1.6	W				
Junction and Storage Temperature Range		$T_J$ , $T_{STG}$	-55 to 175	°C				

Thermal Characteristics								
Parameter	Symbol	Тур	Max	Units				
Maximum Junction-to-Ambient A	t ≤ 10s	Р	14.2	20	°C/W			
Maximum Junction-to-Ambient A	Steady-State	$R_{\theta JA}$	40	50	°C/W			
Maximum Junction-to-Lead <sup>C</sup>	Steady-State	$R_{\theta JL}$	0.56	1.5	°C/W			

#### Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Тур	Max	Units				
STATIC PARAMETERS										
$BV_{DSS}$	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30			V				
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =24V, V <sub>GS</sub> =0V		0.005	1	μА				
		T <sub>J</sub> =55°C			5					
$I_{GSS}$	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ = ±20V			100	nA				
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS} I_{D}=250 \mu A$	1.2	1.8	2.4	V				
$I_{D(ON)}$	On state drain current	$V_{GS}$ =4.5V, $V_{DS}$ =5V	110			Α				
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =20A		4.2	5.2	2 mΩ				
		T <sub>J</sub> =125°C		6	7.5	11122				
		$V_{GS}$ =4.5V, $I_D$ =20A		5.6	7	mΩ				
g <sub>FS</sub>	Forward Transconductance	$V_{DS}=5V$ , $I_{D}=20A$		85		S				
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A,V <sub>GS</sub> =0V		0.7	1	V				
I <sub>S</sub>	Maximum Body-Diode Continuous Current				85	Α				
DYNAMIC	PARAMETERS									
C <sub>iss</sub>	Input Capacitance			6060	7000	pF				
Coss	Output Capacitance	$V_{GS}$ =0V, $V_{DS}$ =15V, f=1MHz		638		pF				
$C_{rss}$	Reverse Transfer Capacitance			355		pF				
$R_g$	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz		0.45	0.6	Ω				
SWITCHI	NG PARAMETERS									
Q <sub>g</sub> (10V)	Total Gate Charge			96.4	115	nC				
Q <sub>g</sub> (4.5V)	Total Gate Charge			46.4	55	nC				
$Q_{gs}$	Gate Source Charge	V <sub>GS</sub> =4.5V, V <sub>DS</sub> =15V, I <sub>D</sub> =20A		13.6		nC				
$Q_{gd}$	Gate Drain Charge			15.6		nC				
t <sub>D(on)</sub>	Turn-On DelayTime			15.7	21	ns				
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =10V, $V_{DS}$ =15V, $R_L$ =0.75 $\Omega$ ,		14.2	21	ns				
t <sub>D(off)</sub>	Turn-Off DelayTime	$R_{GEN}=3\Omega$		55.5	75	ns				
t <sub>f</sub>	Turn-Off Fall Time			14	21	ns				
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =20A, dI/dt=100A/μs		31	38	ns				
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =20A, dI/dt=100A/μs		24	29	nC				

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1in  $^2$  FR-4 board with 2oz. Copper, in a still air environment with T  $_A$  =25°C. The Power dissipation  $P_{DSM}$  is based on steady-state  $R_{\theta JA}$  and the maximum allowed junction temperature of 150°C. The value in any a given application depends on the user's specific board design, and the maximum temperature fo 175°C may be used if the PCB or heatsink allows it.

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B. The power dissipation  $P_D$  is based on  $T_{J(MAX)}$ =175°C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

C: Repetitive rating, pulse width limited by junction temperature  $T_{J(MAX)}=175$ °C.

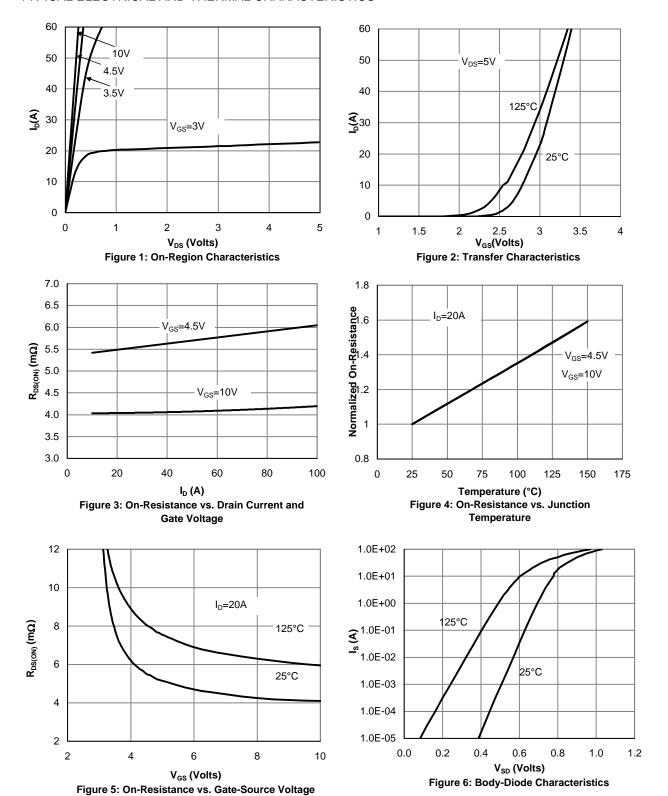
D. The R  $_{0JA}$  is the sum of the thermal impedence from junction to case R  $_{0JC}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using  $<300~\mu s$  pulses, duty cycle 0.5% max.

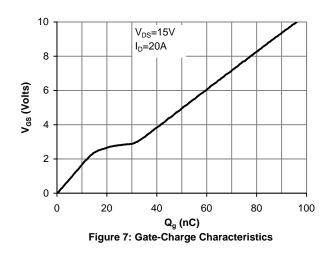
F. These tests are performed with the device mounted on 1 in <sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T <sub>A</sub>=25°C. The SOA curve provides a single pulse rating.

G. The maximum current rating is limited by the package current capability.

### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



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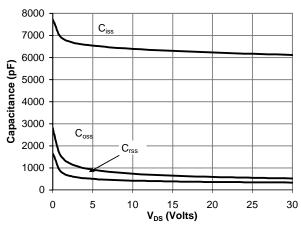
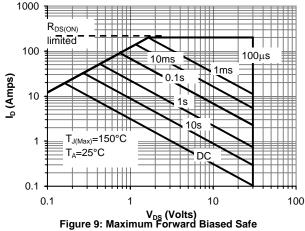


Figure 8: Capacitance Characteristics



Operating Area (Note F)

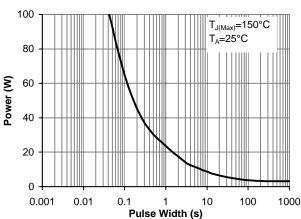


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

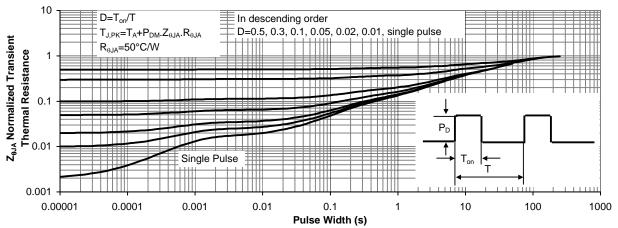


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

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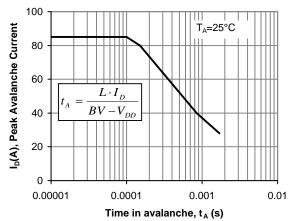


Figure 12: Single Pulse Avalanche capability

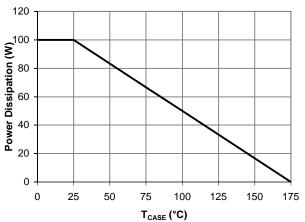


Figure 13: Power De-rating (Note B)

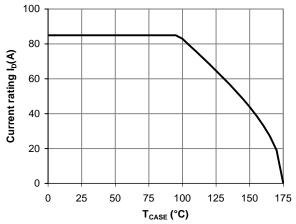


Figure 14: Current De-rating (Note B)